


<b>Search Notes</b>  	<b>Application/Control No.</b>  10511830	<b>Applicant(s)/Patent Under Reexamination</b>  YONEYA, AKIHIKO
	<b>Examiner</b>  TRI H PHAN	<b>Art Unit</b>  2616

SEARCHED			
Class	Subclass	Date	Examiner
370	203-211	03/31/2008	TP
455	207-209, 313-316, 324	03/31/2008	TP

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (USPT,JPO,EPO,FPRS,DWPI) - see text search history printout.	3/31/2008	TP
Frank Duong (consulted search)	3/28/2008	TP

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner